



invites to

TestForum 2026

*A Nordic event for exchange of experience and know-how
within the field of production test of electronics.*

*Meet colleagues and experts, gain knowledge about trends
and best practices in the area, test of electronics.*

Tuesday and Wednesday, December 1st and 2nd, 2026

Swissôtel Tallinn, Estonia



TestForum 2026 December 1st & 2nd, Swissôtel Tallinn, Estonia

Dear Test Professional,

For nearly a quarter of a century, TestForum has been one of the major annual events in the field of testing electronics - at least within Northern Europe. Next year, TestForum will celebrate its 25th anniversary. TestForum is a conference where many test engineers have the opportunity to learn about the latest developments in testing. Attendees draw inspiration from presentations and interactions with colleagues, gaining insights into how they can best address challenges back at their own companies, when ensuring the optimal quality of the products they deliver.

Those, who have participated in TestForum conferences over the years, have witnessed how the field of testing has grown in complexity - much like the underlying technologies that we, as test engineers, are responsible for validating before products reach the customer.

While many methods may still go by the same names—such as JTAG testing, structural testing, functional testing, and the like - their actual contents have changed dramatically. Along the way, new and effective methods have emerged, including optical inspection and X-ray inspection; more recently, there have been impressive advancements driven by artificial intelligence (AI). It has also been fascinating to observe the evolution of "best practices" and to learn, through conversations with colleagues, how various companies are positioning themselves amidst the rapid changes currently transforming the electronics testing sector.

In recent years, a new dimension has entered the realm of testing: **Security** - specifically threats such as hacker attacks, hybrid warfare, and similar risks have now become significant factors in how we structure our testing efforts - and which tools and strategies we can employ. We must constantly consider how to prevent test access to products from being exploited to cause harm once those products reach the customers.

At TestForum 2026, primary focus is on Cybersecurity, the Cyber Resilience Act (CRA), and other security issues related to the testing of electronics. We are navigating an entirely new landscape that we need to master, and you certainly won't be disappointed by the insights and solutions offered in many of this year's presentations.

I can confidently promise that you won't leave TestForum 2026 disappointed - whether the topic is the latest developments in testing methodologies or, for instance, cybersecurity. Look forward to an exciting TestForum 2026!

Yours sincerely



Knut Båtsstøløy
Chairman of Nordic Test Forum



Keynote Speaker Steve Summers, Emerson's Test & Measurement Business

'How cybersecurity and the CRA will change your job as a test engineer'

The need to secure data systems is increasing daily. Attackers are growing more sophisticated, and the financial rewards of a successful attack have ballooned in size. AI is giving these attackers new tools with advanced capabilities. In response, the EU Cyber Resilience Act applies new requirements to any products delivered into the EU. Test teams are feeling the pressure to adopt new security practices into their workflows.



Steve Summers

Director, Mechanical Test, Aerospace and Defense Industries. Security Lead
Emerson's Test and Measurement Business – NI

How will this regulation, and the drive toward more cyber secure systems, change the way you build, deploy and maintain test systems? This keynote examines cybersecurity through the lens of test engineering, connecting real-world incidents with decisions about software dependencies, supplier readiness and systems that must remain secure throughout their working lives. It explores how AI is changing vulnerability discovery and why teams need to prepare for more frequent security updates.

Drawing on perspectives from Emerson/NI and Hampel Software Engineering, the session combines the regulatory picture with a small engineering company's experience of building a repeatable security program. We will discuss secure development practices, risk assessments, software bills of materials (SBOMs), vulnerability handling and evidence of conformity. We will introduce security resources to bring these concepts into the test development workflow.

Whether you develop test software, design automated test systems or lead an engineering team, you will leave with a clearer understanding of where to start, what to ask your suppliers and how to make cybersecurity part of everyday engineering.

Executive Bio for Steve Summers

Steve Summers is a Director at Emerson and is the Security Lead for the aerospace industry. In prior roles at Emerson, Steve introduced the LabVIEW Center of Excellence program, revamped NI's license programs, and led the transition of the Customer Education program to provide more online options. He has focused on the aerospace industry for the last 7 years, where he manages the mechanical test market segment, which is primarily DAQ and real-time test including CompactRIO.

As Security Lead, Steve interfaces with customers to understand security regulations and the impact that cybersecurity has on test engineering teams. He works with Emerson's R&D teams to build security into the NI products, and communicates important security information out to the NI user community. Among other efforts, he hosts a semiannual security user group to bring test engineers and security experts together.

He earned a degree in Physics at Brigham Young University and has worked in roles as an application engineer, sales engineer, account owner, and product manager. He has worked in the test and measurement industry for more than 25 years.

Nordic Test Forum in Brief

TestForum is an annual event run by *Nordic Test Forum (NTF)* every fall/early winter. *TestForum* typically has 4-5 thematic areas and cover a broad balance of test and inspection.

TestForum has its roots back the late eighties, where it originated as an event for the Norwegian electronics industry. However, from the late part of 2001 a group of people from Norway, Sweden and Denmark established the network community, *Nordic Test Forum*. Later on, this activity (including the *TestForum* event) was extended to include all Nordic countries and the Baltic States. The language of the official presentations is English. Content and focus of the *TestForum* varies over time, but always within topic areas in focus at a given point in time.

TestForum has its main emphasis on issues relevant to production managers, engineers and technicians working in the fields of production, test, inspection and validation of electronics. At *TestForum* events we offer technically relevant presentations on methodology, tools, modules/instruments and available technology. The interaction between users and suppliers within the focus areas is an important asset of *TestForum*, and this balance and interaction is pursued in presentations, panel discussions, networking, show cases at the attached exhibition and in the planning of the events.

TestForum Aims at:

- Creating and sustaining a relevant, balanced and coherent interaction between users as well as between users and suppliers of solutions for test, inspection, validation and production of electronics.
- Providing an up-to-date view on new methodologies and tools for relevant test, inspection, validation and production of electronics.
- Establishing a relevant and balanced view on equipment, systems, tools and software from tool vendors in the domain.

Target Audience of TestForum

Engineers and technicians, managers and planners within the fields of electronics production and test, inspection and validation. Includes also decision makers in organizations that procure equipment, tools and systems for production and test, inspection and validation of electronics.

Executive Committee of TestForum event and NTF organization

Knut Båstoløkken, Kitron AS, Norway (Chairman)
Birger Schneider, CHAMAJ Consult ApS, Denmark (Treasurer)
Mika Pussinen, Nokia, Finland (Secretary)
Artur Jutman, Testonica Lab OÜ, Estonia
Erik Larsson, Lund University, Sweden
Harri Korhonen, Oitec OY, Finland
Martin Østergaard, GPV International A/S, Denmark
Mats Klarholm, Columbia Elektronik, Sweden
Mattias Ericsson, Questit, Sweden
Paulius Musteikis, UAB Kitron, Lithuania
Raimesdas Sodaitis, EP-TeQ UAB, Lithuania
William Baars, CN Rood (associate member), The Netherlands

Become a Member of Nordic Test Forum

If you are involved in production test, validation test, and inspection of electronics and your professional work is related to activities in the Nordic countries as a test professional, design engineer, manufacturer, supplier of solutions, consultant, etc., you may register as member of Nordic Test Forum (NTF) in order to benefit from:

- Exchange of know-how in testing
- Increased contact network in the Nordic countries
- Surveillance and information of international activities in test and inspection
- Discounts at NTF seminars and TestForum events

Please register on the WEB page: <http://www.NordicTestForum.org>

TestForum 2026 Local Organizer

Artur Jutman

Testonica Lab OÜ
Akadeemia tee 15A,
12618 Tallinn, Estonia
Phone: +372 5333 2551
Email: artur@testonica.com

Conference secretariat

Jytte Schneider

CHAMAJ Consult ApS
Skovgraensen 3, DK-2960
Rungsted Kyst, Denmark
Phone: +45 2579 1120
Email: jytte.schneider@nordictestforum.org

Technical Program of TestForum 2026

Nordic Test Forum (NTF) Annual Assembly, November 30th, 2026

The NTF organization holds an annual general assembly a day before the TestForum conference. This year it will be held on **November 30th at 20:00**. The agenda and motions have been dispatched to the members in a separate mailing.

Tuesday, December 1st, 2026

Time	Titles	Speakers or additional info
08:15-08:30	Registration	
08:30-08:40	Welcome / Introduction	Knut Båttstøløyken
08:40-09:40	KeyNote Session	Chairman: Knut Båttstøløyken
08:40-09:40	How cybersecurity and the CRA will change your job as a test engineer	Steve Summers, Emerson Test and Measurement (NI)
09:40-10:20	Exhibitor Forum: short presentations	Chairman: Artur Jutman
10:20-11:00	Coffee Break / Exhibition	
11:00-12:30	Session 1: Structural test 1 / Test strategies	Chairman: Mika Pussinen
11:00-11:30	1.1 The Evolution of Testing: How AI empowers Test Program Generation	Lothar Diez, SPEA
11:30-12:00	1.2 ULTRA technology: A must to meet hyperscalers' test needs	Andrea Romano, Seica
12:00-12:30	1.3 From DFT to Production Confidence: Practical Strategies for Modular, High-Coverage Electronics Test	Vojtech Camfrla, UNITES Systems a.s.
12:30-13:30	Lunch	
13:30-15:00	Session 2: Structural test 2 / Test Automation	Chairman: Paulius Musteikis
13:30-14:00	2.1 Faster inspection with deeper insight & Intelligent verification station	Chanderkant Vaid, GÖPEL electronic GmbH
14:00-14:30	2.2 Next level thermal imaging for detecting open ends for non-destructive validation testing	Dirk Faber, CN Rood
14:30-15:00	2.3 The Next Test Bottleneck: Scaling Electronics Production Without Scaling Labor	Dragos-Andrei Beldiman, Brooks
15:00-15:40	Coffee Break / Exhibition	
15:40-17:10	Session 3: IJTAG / Security	Chairman: Raimondas Sodaitis
15:40-16:10	3.1 IJTAG in Practice: Where Interoperability Still Breaks, and What Is Being Done About It	Reginald Waller, Asset Intertech
16:10-16:40	3.2 Security Challenges in Design-for-Test Across the Silicon Lifecycle	Erik Larsson, Lund University
16:40-17:10	3.3 The evolution of CAD formats in the electronics industry	Hermann Reischer, Polar Instruments GmbH
17:10-17:40	Fruit & Refreshments / Exhibition	
17:40-19:00	Panel debate:	Panel moderator: Birger Schneider
	Cybersecurity, Cyber Resilience Act (CRA) and Other Security Issues in Testing of Electronics	
19:30	Gala Dinner	

Wednesday, December 2nd, 2026

Time	Titles	Speakers or additional info
08:30-10:00	Session 4: Test data analysis	<i>Chairman: Erik Larsson</i>
08:30-09:00	4.1 Test data analysis with WATS Alvea and MCP	Natanya Sukkot, Virinco
09:00-09:30	4.2 Finding the Signal in the Noise: Hidden Insights from Manufacturing Test Data	Yee Shuen Hung, Keysight Technologies
09:30-10:00	4.3 PCB Repair and Rework with AI That Knows the Board and Its History	Giorgio Insinga, ARBoard
10:00-10:45	Coffee Break / Exhibition	
10:45-12:15	Session 5: JTAG based test / RF test	<i>Chairman: Mattias Ericsson</i>
10:45-11:15	5.1 Embedded ISP in combination with JTAG Embedded Test	Jan Heiber, Göpel electronic
11:15-11:45	5.2 Using freely available libraries and tools to enhance JTAG Functional Test	Anthony Sparks, JTAG Technologies
11:45-12:15	5.3 From Model to RF: Practical Prototyping and Validation for Next-Generation Wireless Systems	Aku Wilenius, CN Rood
12:15-13:30	Lunch	
13:30-15:00	Session 6: AI	<i>Chairman: Mats Klarholm</i>
13:30-14:00	6.1 Why AI is Becoming Essential in Test—and How Nigel Enables It	Steve Summers, Emerson Test and Measurement (NI)
14:00-14:30	6.2 Accelerating Test Development with AI: Keysight's Open TAP Approach and Vision	Xavier Lory, Keysight
14:30-15:00	6.3 AI engineered functional test: agent-controlled instrumentation with MCP interface	Artur Jutman, Testonica
15:00-15:15	Short break	
15:15-16:15	Session 7: Functional test /	<i>Chairman: Harri Korhonen</i>
15:15-15:45	7.1 Testblox, A new integrated in-fixture instrumentation platform for automated functional test	Bo Öhrwall , CEO Testblox AB
15:45-16:15	7.2 AI Solution for ICT & AOI and High-Speed AXI	Anthony Wang, TRI Test Research Europe GmbH
16:15-16:60	Closing Session: TestForum concluding remarks	<i>Knut Båttstøløkken, Kitron</i>

Exhibition

As usual, a mini exhibition takes place in frames of TestForum event where vendors present their tools and methodologies related to production tests.

Exhibitors can make arrangements with NTF about the exhibition space. If nothing special has been agreed, a table of about 40x120 cm², a 230V power connection as well as space for posters or similar material will be provided. Every exhibitor will be given 3-minute slot in the program for a brief introduction (max 3 PowerPoint slides) during the Exhibitor Forum on Tuesday morning. Please contact the secretariat about special requirements.

The exhibitor fee also includes participation for one person. See the registration section for details

TestForum registration and hotel booking

TestForum conference registration

Register for TestForum 2026 using the online registration form:

<https://testforum.nemtilmeld.dk/7/>

The conference fee includes participation in **TestForum 2026**, food and refreshments from conference start Tuesday morning to Wednesday afternoon at conference finish as well as conference proceedings. Proceedings are available for downloading containing the contributions made available by their authors.

Hotel accommodation is booked and paid for separately, see below.

The conference fee is invoiced to the participant's organization. Cancellation of the tickets is possible as specified in the Terms of Registration. On failure to attend, the full fee remains payable. On request, another person from the same organization may attend instead.

Participant category	Conference fee
NTF member	EUR 705
Non-member	EUR 810
Student with valid student ID	EUR 370
Exhibitor — booth rental and one participant	EUR 1,265

Hotel booking

Book accommodation directly with Swissôtel Tallinn through the dedicated event booking link:

- <https://book.passkey.com/event/51248558/owner/50966718/home>

Booking a room at the conference hotel is **not** mandatory for participation at the event.

Please note that hotel rooms at the conference hotel is only guaranteed up to **Saturday 31 October**. **Registration to TestForum 2026 after this date is still possible**. However, we cannot guarantee that hotel rooms are available at the conference hotel beyond the notified date.

For registration assistance, contact the TestForum secretariat at:

Jytte Schneider

Phone: +45 2579 1120

Email: jytte.schneider@nordictestforum.org

Note: You may also check the NTF website for recent updates in information. www.nordictestforum.org

Conference Hotel:

Swissôtel, Tallinn, Estonia

TestForum 2026 will take place at Swissôtel Tallinn located at the heart of Tallinn's business center and within only a short stroll from the medieval **Old Town**, a UNESCO World Heritage Site with distinctive cobblestone streets, cozy cafes, lively pubs, and gourmet restaurants.

Swissôtel Tallinn, the tallest building in the city, boasts impressive views of the old town and the Baltic Sea, while offering its guests a world of ease, luxury and Swiss hospitality. The hotel's Spa & Sport center offers a wide selection of treatments, from hydrotherapy to hot stone massages, providing a perfect retreat after a long conference day.

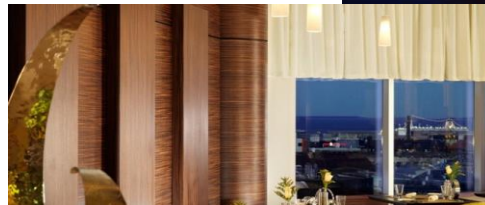
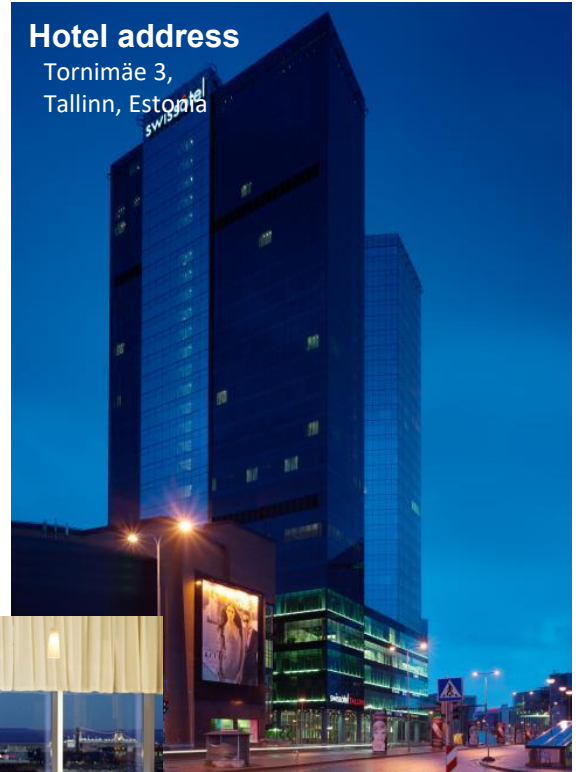
The location in the very heart of the city brings all possible adventures in Tallinn close together giving you the possibility to find yourself in the middle of the city life or enjoy its peace and quietness. The business area, tourist sights and museums, major attractions and theatres are easily accessible on foot. Tallinn's International Airport is only 10 minutes away by car.

More details about the hotel at:

<https://www.swissoteltallinn.com>

Hotel address

Tornimäe 3,
Tallinn, Estonia



Traveling to and from Tallinn

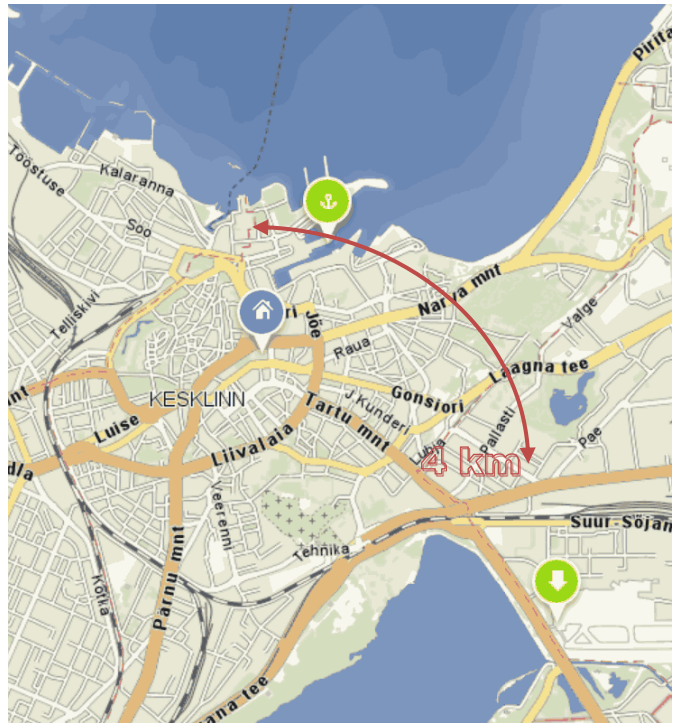
Tallinn is well accessible by plane, ferry, train, and bus. Below we summarize the most common ways to reach the city. However, for the most up to date travel hints and tourist information, see [Wikitravel](https://www.wikitravel.org/wiki/en/Tallinn)

By Plane

Tallinn Airport (TLL) is situated just 4 km away from Tallinn downtown and the NTF venue. The full list of connections and carriers together with the full timetable is available at the [Tallinn Airport's home page](https://www.tallinnairport.ee/en).

The most convenient way to travel from the airport to downtown is by taxi where the normal fare is approximately 10 EUR. In many taxis you can use major credit cards (VISA, Eurocard/MasterCard) besides paying in cash.

The public bus no. 2 or tram no. 4 are budgetary alternatives to the taxi. The journey to the downtown takes 15-20 minutes. Single-ride tickets sold on internet (QR-ticket) cost 1€. The ticket sold by the driver costs 2€. More information about ticket types and purchase options is available [here](https://www.tallinn.ee/en/tickets).



By Ferry

The Port of Tallinn is connected by sea routes to Stockholm, Helsinki and St. Petersburg. There are a dozen journeys per day to/from Helsinki and one daily departure to/from Stockholm. The timetable can be found [here](https://www.tallinnport.ee/en). The Passenger Port is located very close to the Old Town but probably not on a walking distance to the conference hotel. The best way to reach the conference location from the port is a taxi (3-4-minute ride). Public bus no. 2 can be also used.

By Bus

There are bus connections to Baltic Countries, Poland, Germany, Russia, and other places in Europe. The Tallinn bus terminal is located just 1 km away from the conference venue.

By Train

There is a railway connection from Tallinn to St. Petersburg and Moscow. For details [click here](https://www.rail.ee/en).

Map of Tallinn downtown

Please note that the conference dinner on December 1st will be held outside the conference hotel. We will visit a medieval restaurant called '**Peppersack**' located next to the Town Hall square in the Old Town 1 km away from the conference hotel.

All Test Forum participants are kindly requested to be in the hotel lobby at **19:15** where we will start our walk to the restaurant.

